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ABSTRACT

The Scan-Tron Forms Analysis Package (SFAP) is a collection of integrated programs that allow an IBM-PC (or compatible) to collect data from a Scan-Tron 1200 forms reader. In addition to the basic data acquisition capability, the SFAP has additional capabilities related to the viewing and formatting of incoming data. When used in combination with the Test Analysis Package or the Student-Problem Package, the SFAP provides an easy and manageable link between raw data and organized results. The SFAP provides four primary options: (1) reading of forms using the Scan-Tron 1200; (2) data conversion from raw data to an 80-column card image; (3) viewing and printing of data files; and (4) creation of new form parameters. (TJH)

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